

<b>Issue Classification</b>				Application/Control No.		Applicant(s)/Patent under Reexamination	
				10/748,229		KIM ET AL.	
				Examiner		Art Unit	
				Devin Hanan		3745	

ORIGINAL				CROSS REFERENCE(S)									
CLASS		SUBCLASS		CLASS		SUBCLASS (ONE SUBCLASS PER BLOCK)							
415		58.4		415		176							
INTERNATIONAL CLASSIFICATION				416		181							
F	2	5	D	17/4									
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<i>Devin Hanan</i> 2/14/06 Devin Hanan 2/14/2006 (Assistant Examiner) (Date)				<i>Edward K. Look</i> 2/15/06 EDWARD K. LOOK SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 3700 (Primary Examiner) (Date)				Total Claims Allowed: 1-25					
<i>K Cooper</i> 2/15/06 (Legal Instruments Examiner) (Date)								O.G. Print Claim(s)		O.G. Print Fig.			
								1		2			

<input checked="" type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R. 1.47	
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